

**Notice of References Cited**

Application/Control No.

10/742,695

Applicant(s)/Patent Under  
Reexamination  
QADEER ET AL.

Examiner

Saif A. Alhija

Art Unit

2128

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Tyrrell et al. "CSP Methods for Identifying Atomic Actions in the Design of Fault Tolerant Concurrent Systems" IEEE 1995
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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